



Exhibitor Introduction

※ Please write it in English.

Name of Company	Park Systems	
President	Sang-il Park	
Address	KANC 4F, 109 Gwanggyo-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16229, Korea	
Website	http://parksystems.com	
E-mail	inquiry@parksystems.com	
Tel.	031-546-6800	
Exhibitor Introduction	<p>Park Systems Corporation is a leading provider of nanoscale microscopy and metrology solutions. Its comprehensive product range includes atomic force microscopy (AFM), white light interferometry (WLI), nano-infrared spectroscopy (NanoIR), imaging spectroscopic ellipsometry (ISE), and active vibration isolation (AVI) systems. The company's commitment to innovation has led to groundbreaking technologies like True Non-Contact imaging, 3D metrology, and fully automated AFM systems, serving both research and industrial applications. These solutions are widely used in scientific research, nanoscale engineering, semiconductor fabrication, display technology, advanced packaging, and quality assurance. Park Systems' dedication to excellence has made it the preferred choice for nano-metrology products among leading semiconductor companies, top-tier research universities, and national labs.</p>	
Exhibit Description	<p>Material Science & Chemistry</p> <p>The versatility of Park AFMs allows them to serve as the optimal nanometrology solutions within the materials science and chemistry fields, wherein nanometrology is employed to characterize the properties and behavior of nanoscale materials and molecules. With the capability to characterize materials' electrical, magnetic, mechanical, and morphological properties, Park AFMs offers specialized operating modes that empower materials researchers to advance their understanding and control of nanoscale behavior. They also enable chemistry scientists to scale up their research on the chemical composition, structure, and reactivity of nanoparticles, nanocomposites, and other nanoscale materials.</p> <p>Semiconductor & Display</p> <p>With a full line of automated AFMs for semiconductor fabrication metrology, device failure analysis and other industrial applications, Park Systems possesses a portfolio that is ready to meet the needs of the semiconductor and display industry—precise measurement and control of nanoscale structures that are crucial for device fabrication and performance optimization. Park AFM solutions allow engineers to take highly accurate, repeatable, and complete measurements, thereby increasing the manufacturing efficiency and resulting quality of production.</p>	
Exhibit Product	<p>AFM (Atomic Force Microscope): Park FX40</p>	

